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Beam Monochromator Design and Implementation; 3.4 XHR Systems and Applications; 3.5 Conclusions; Acknowledgements; References
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Sommario/riassunto

"Part of the Wiley-Royal Microscopical Society Series, this book discusses the rapidly developing cutting-edge field of low-voltage microscopy, a field that has only recently emerged due to the rapid developments in the electron optics design and image processing. It serves as a guide for current and new microscopists and materials scientists who are active in the field of nanotechnology, and presents applications in nanotechnology and research of surface-related phenomena, allowing researches to observe materials as never before"

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